Search Notes



Application/Control No.	Applicant(s)/Patent u Reexamination	nder
10/005,778	LI ET AL.	
Examiner	Art Unit	
Frin M File	2634	

Subclass	Date	Examiner
343	12/17/2004	EMF
796	12/17/2004	EMF
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		796 12/17/2004

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
375	316	12/17/2004	EMF	
375	340	12/17/2004	EMF	
375	343	12/17/2004	EMF	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST US PAT, USPGPUB, EPO, JPO DERWENT, IBM	12/17/2004	EMF		
PALM INVENTORSHIP	12/17/2004	EMF		
IEEE Explore Keyword Search	12/20/2004	EMF		
IEEE Explore Article Search	12/20/2004	EMF		
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